# Phase transitions of MgF<sub>2</sub> under high pressure and high temperature

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## **Introduction**

There have been many investigations of post-rutile type structures under high pressure in the field of earth science, crystallography, and solid state physics and chemistry since synthesis of rutile type  $SiO_2$ . Haines *et al.* investigated high-pressure phase transitions of MgF<sub>2</sub> at room temperature as a simple model of the high-pressure behavior of  $SiO_2$ . However, the high-pressure and high-temperature behavior of MgF<sub>2</sub> was not been reported. Recently, we observed the behavior by using an *in-situ* X-ray diffraction method [1]. We introduce the result in this report.

#### **Experimental**

X-ray diffraction patterns were collected by an energydispersive type method using a large volume cubic press apparatus "MAX80" at PF-AR-NE5C. The detail of highpressure and high-temperature experiments was described in our article [1].

## **Result and discussion**

Three high-pressure phases were observed in the pressure range up to 15 GPa. Figure 1 shows typical X-ray powder diffraction patterns of MgF<sub>2</sub>, collected by energy-dispersive method. The X-ray diffraction pattern of the ambient-pressure phase with the rutile structure  $(P4_2/mnm, Z = 2)$ , as shown in Fig. 1-a, was broadened by increasing pressure under solid state compression at room temperature.

Figure 1-b shows the X-ray diffraction pattern of the high-pressure phase with the CaCl<sub>2</sub>-type structure (*Pnnm*, Z = 2) at 11.1 GPa and 27°C, collected after annealing at 500°C.

Some new diffraction lines except for those of the CaCl<sub>2</sub>-type phase emerged by elevating temperature at 13 GPa. All diffraction lines from the CaCl<sub>2</sub>-type phase vanished and the new diffraction lines were only observed at 12.7 GPa and 750°C, as shown in Fig. 1-c. All observed diffraction lines could be indexed on an orthorhombic cell. The indices and relative intensities of the diffraction lines (Fig. 1-c) indicated that the highpressure phase has the  $\alpha$ -PbO<sub>2</sub> type structure (*Pbcn*, Z = 4). The  $\alpha$ -PbO<sub>2</sub> type phase with a trace of the rutile-type phase was finally recovered at ambient condition. The volume per chemical formula of the  $\alpha$ -PbO<sub>2</sub> type phase was 1.1% smaller than that of the rutile-type phase at ambient condition. The bulk modulus of the  $\alpha$ -PbO<sub>2</sub> type phase was determined to be  $K_0 = 98.0 \pm 0.7$  GPa by fitting the P - V data to the third-order Birch-Murnaghan

equation of state with  $K^2 = 4$ . The  $\alpha$ -PbO<sub>2</sub> type phase was also confirmed to have a stable region nearby 13 GPa and 600°C.

Another high-pressure phase with the  $PdF_2$  type structure (*Pa-3*, Z = 4) was observed at 14.7 GPa and 650°C, as shown in Fig. 1-d.

The present investigation is the first discovery of the stable  $\alpha$ -PbO<sub>2</sub> type phase in fluoride compounds. This discovery suggests that high-pressure behavior of difluoride compounds with the rutile structure is similar to that of dioxides and that the stable  $\alpha$ -PbO<sub>2</sub> type phase of other difluoride compounds will be found under high pressure and high temperature.



Fig. 1 Typical energy-dispersive type X-ray diffraction patterns of MgF<sub>2</sub>, taken at  $2\theta = 6.99^{\circ}$  [1].

## **Reference**

[1] K. Kusaba *et al.*, Solid State Commun., **148**, 440 (2008).

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